RELIABILITY MONITOR

DS1210S JUL '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210S	C1	9813	DN801581AAC	16 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 3.0 µ POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22330	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22398	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22213	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22399	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22400	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22401	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1232L OCT '98 MONITOR-HYUNDAI,KOREA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232L	C1	9830	DL817678ABB	8 PIN SOIC	HYUNDAI-KOREA (HEI)

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22755	INFANT LIFE	125°C, 7.0 VOLTS		232	48	HOUR	0
P22778	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22674	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22779	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22781	AUTOCLAVE	121°C STEAM, UNBIASED		37	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1232S JUL '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232S	C1	9821	DL809263AAC	16 PIN SOIC	HYUNDAI-KOREA (HEI)

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22324	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22370	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22222	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22371	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22372	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22373	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1233 JUL '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9828	DM819256ABA	SOT-223	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22421	INFANT LIFE	125°C, 7.0 VOLTS		229	48	HOUR	0
P22521	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS:	3.07E+07	0
P22348	HIGH TEMP STORAGE	125°C		233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		233	3	PASS	0
		TOTAL:					0
P22522	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22523	HAST	120°C, 85%R.H.,5.5V		71	100	HOUR	0
		TOTAL:					0
P22524	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1233Z OCT '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233Z	A5	9836	DM819258ACA	SOT-223	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22753	INFANT LIFE	125°C, 7.0 VOLTS		229	48	HOUR	0
P22782	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P22676	HIGH TEMP STORAGE	125°C		233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		233	3	PASS	0
		TOTAL:					0
P22783	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22784	HAST	120°C, 85%R.H.,5.5V		72	100	HOUR	0
		TOTAL:					0
P22785	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1267E AUG '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1267	A1	9824	DK745514ABB	20 PIN TSSOP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Single Metal 1.2 µ Implanted poly1

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22597	INFANT LIFE	125°C, 6.0V,-4.0V		229	48	HOUR	0
P22660	HIGH VOLTAGE LIFE	125°C, 6.0V,-4.0V		77	336	HOUR	0
		125°C, 6.0V,-4.0V		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS:	1.13E+07	0
P22495	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22661	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22662	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22663	AUTOCLAVE	121°C STEAM, UNBIASED		34	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1267 NOV '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1267E	A1	9823	DK803107AAE	20 PIN TSSOP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Single Metal 1.2 µ Implanted poly1

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P23026	INFANT LIFE	125°C, 6.0V,-4.0V		233	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	646	DEVICE HRS:	1.42E+06	0
P22791	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0

RELIABILITY MONITOR

DS1302 JUN '98 MONITOR-ANAM KOREA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	A3	9808	DN750310ABC	8 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22282	INFANT LIFE	125°C, 6.0 VOLTS		234	48	HOUR	0
P22349	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS: 1.13E+07		0
P22211	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22350	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22351	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				76	959	HOUR	0
		TOTAL:					0
P22352	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1302Z SEP '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302Z	A3	9829	DK817643ACA	8 PIN PDIP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1
Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22691	INFANT LIFE	125°C, 6.0 VOLTS		234	48	HOUR	0
P22734	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS: 1.13E+07		0
P22735	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22736	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22737	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1315 SEP '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1315	B1	9825	DK806519AAA	16 PIN PDIP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22496	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22536	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22537	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22538	HAST	120°C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
P22539	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1620 JUN '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9741	DJ723284AAF	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22198	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
P22287	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.09E+07		0
P22129	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22288	TEMP CYCLE	-55 TO 125°C		39	300	CYCL	0
				33	1000	CYCL	0
		TOTAL:					0
P22289	HAST	120°C, 85%R.H.,5.5V		70	100	HOUR	0
		TOTAL:					0
P22409	HIGH TEMP STORAGE	150°C		46	336	HOUR	0
				46	1000	HOUR	0
		ELEC TEST		45	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1620 MAR '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9746	DJ723286AAC	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

PROCESS Single Poly, Single Metal 1.2 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22173	INFANT LIFE	125°C, 7.0 VOLTS		232	48	HOUR	0
P22271	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		72	336	HOUR	0
		125°C, 7.0 VOLTS		72	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	32	DEVICE HRS: 2.90E+07		0
P22067	HIGH TEMP STORAGE	125°C		236	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		236	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		236	3	PASS	0
		TOTAL:					0
P22272	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22273	HAST	120°C, 85%R.H.,5.5V		70	100	HOUR	0
		TOTAL:					0
P22408	HIGH TEMP STORAGE	150°C		47	336	HOUR	0
				45	1000	HOUR	0
		ELEC TEST		45	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1620S SEP '98 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9746	DJ711527ABD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22599	INFANT LIFE	125°C, 7.0 VOLTS		230	48	HOUR	0
P22707	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P22501	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22708	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22709	HAST	120°C, 85%R.H.,5.5V		70	100	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1621 JUN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9745	DM734572AAD	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22200	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
P22283	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		71	336	HOUR	0
		125°C, 7.0 VOLTS		71	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	32	DEVICE HRS: 2.87E+07		0
P22131	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22284	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				36	1000	CYCL	0
		TOTAL:					0
P22285	BIASED MOISTURE	85/85, 5.5 VOLTS		70	274	HOUR	0
				70	959	HOUR	0
		TOTAL:					0
P22337	HIGH TEMP STORAGE	150°C		43	336	HOUR	0
				43	1000	HOUR	0
		ELEC TEST		43	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1621 JUN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9745	DM734572AAD	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS

RELIABILITY MONITOR

DS1621S MAR '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9749	DM705419ABA	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22276	INFANT LIFE	125°C, 7.0 VOLTS		230	48	HOUR	0
P22342	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		68	336	HOUR	0
		125°C, 7.0 VOLTS		67	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	34	DEVICE HRS: 2.72E+07		0
P22202	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22343	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				39	1000	CYCL	0
		TOTAL:					0
P22344	BIASED MOISTURE	85/85, 5.5 VOLTS		68	274	HOUR	0
				68	959	HOUR	0
		TOTAL:					0
P22460	HIGH TEMP STORAGE	150°C		50	336	HOUR	0
				50	1000	HOUR	0
		ELEC TEST		50	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1621S MAR '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9749	DM705419ABA	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS

RELIABILITY MONITOR

DS1621S SEP '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A7	9807	DN744346ABA	8 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22590	INFANT LIFE	125°C, 7.0 VOLTS		236	48	HOUR	0
P22656	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.09E+07		0
P22503	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		240	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		240	3	PASS	0
		TOTAL:					0
P22657	TEMP CYCLE	-55 TO 125°C		39	300	CYCL	0
				39	1000	CYCL	0
		TOTAL:					0
P22658	BIASED MOISTURE	85/85, 5.5 VOLTS		70	274	HOUR	0
				70	959	HOUR	0
		TOTAL:					0
P22739	HIGH TEMP STORAGE	150°C		45	336	HOUR	0
				45	1000	HOUR	0
		ELEC TEST		45	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1621S SEP '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A7	9807	DN744346ABA	8 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS

RELIABILITY MONITOR

DS17485 FEB.'98 MONITOR,D.P.-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9730	DN713701AAE	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22032	INFANT LIFE	125°C, 7.0 VOLTS		230	48	HOUR	0
P22303	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		76	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.04E+07		0
P21607	HIGH TEMP STORAGE	125°C		237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		237	3	PASS	0
		TOTAL:					0
P22304	TEMP CYCLE	-55 TO 125°C		50	300	CYCL	0
				50	1000	CYCL	0
		TOTAL:					0
P22305	HAST	120°C, 85%R.H.,5.5V		63	100	HOUR	0
		TOTAL:					0
P22306	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS17485 MAY '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9814	DN803023AAD	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22308	INFANT LIFE	125°C, 7.0 VOLTS		230	48	HOUR	0
P22467	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P22010	HIGH TEMP STORAGE	125°C		237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		237	3	PASS	0
		TOTAL:					0
P22468	TEMP CYCLE	-55 TO 125°C		48	300	CYCL	0
				48	1000	CYCL	0
		TOTAL:					0
P22469	HAST	120°C, 85%R.H.,5.5V		65	100	HOUR	0
		TOTAL:					0
P22470	AUTOCLAVE	121°C STEAM, UNBIASED		38	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS17485 AUG '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9819	DN807687AAA	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22472	INFANT LIFE	125°C, 7.0 VOLTS		233	48	HOUR	0
P22526	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22378	HIGH TEMP STORAGE	125°C		237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		237	3	PASS	0
		TOTAL:					0
P22527	TEMP CYCLE	-55 TO 125°C		49	300	CYCL	0
				49	1000	CYCL	0
		TOTAL:					0
P22528	HAST	120°C, 85%R.H.,5.5V		65	100	HOUR	0
		TOTAL:					0
P22529	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1803-010 NOV '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16PN, 150 MIL SOIC	HYUNDAI-KOREA (HEI)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22798	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
		TOTAL:				0

RELIABILITY MONITOR

DS1869 DECEMBER '98 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1869	A3	9829	DJ821533ABB	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22900	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
		TOTAL:				0

RELIABILITY MONITOR

DS2108 AUG '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9747	DN722653BAB	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 5.0 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22456	INFANT LIFE	125°C, 6.0 VOLTS		234	48	HOUR	0
P22484	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS: 1.13E+07		0
P22382	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		238	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22485	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22486	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				76	959	HOUR	0
		TOTAL:					0
P22487	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2109 DEC '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2109S	A7	9836	DM811524AA-	28 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P23110	INFANT LIFE	125°C, 7.0 VOLTS		233	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	234	DEVICE HRS:	3.91E+06	0
P22903	HIGH TEMP STORAGE	125°C		237	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		237	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		237	3	PASS	0
		TOTAL:					0
P23157	HAST	120°C, 85%R.H.,5.5V		65	100	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2153Q SEP '98 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9749	DN733468AAB	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Double Poly, Single Metal 0.8 µ Capacitor

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22556	INFANT LIFE	125°C, 6.0 VOLTS		236	48	HOUR	0
P22637	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS:	1.13E+07	0
P22498	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22638	TEMP CYCLE	-55 TO 125°C		60	300	CYCL	0
				60	1000	CYCL	0
		TOTAL:					0
P22639	AUTOCLAVE	121°C STEAM, UNBIASED		98	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2153Q DEC '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9833	DN811539AAB	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Double Poly, Single Metal 0.8 µ Capacitor

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P23108	INFANT LIFE	125°C, 6.0 VOLTS		237	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	627	DEVICE HRS:	1.46E+06	0
P22905	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0

RELIABILITY MONITOR

DS2165Q OCT '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2165	B1	9837	DN811583AAB	28 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 1.2 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22757	INFANT LIFE	125°C, 7.0 VOLTS		236	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	232	DEVICE HRS:	3.94E+06	0
P22681	TEMP CYCLE	-55 TO 125°C		241	10	CYCL	
	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0

RELIABILITY MONITOR

DS2175S JUL '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2175S	D1	9811	DN803119AAE	16 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 2.0 µ Pfield

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22328	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22402	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22227	TEMP CYCLE	-55 TO 125°C		238	10	CYCL	
	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22403	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22404	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22405	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2181A AUG '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2181	A2	9808	DN751456AAC	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 2.0 µ Pfield

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22480	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
P22918	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P22384	TEMP CYCLE	-55 TO 125°C		241	10	CYCL	
	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22919	TEMP CYCLE	-55 TO 125°C		60	300	CYCL	0
				60	1000	CYCL	0
		TOTAL:					0
P22921	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS21S07AE AUG '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9820	DM807703AAE	20 PIN TSSOP	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22466	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22488	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS:	3.08E+07	0
P22380	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22489	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				39	1000	CYCL	0
		TOTAL:					0
P22490	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				74	959	HOUR	0
		TOTAL:					0
P22491	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS21S07AE NOV '98 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9825	DK809216ACB	20 PIN TSSOP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Single Metal 0.8 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22912	INFANT LIFE	125°C, 7.0 VOLTS		231	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	237	DEVICE HRS:	3.87E+06	0
P22800	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P23130	AUTOCLAVE	121°C STEAM, UNBIASED		37	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS232 SEP '98 MONITOR - OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747726AAA	16 PIN PDIP	OMEDATA

PROCESS Single Poly, Single Metal 5.0 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22499	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22545	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22546	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22547	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22548	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2401 SEP '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9814	DM747716ACA	TO-92	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22504	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22532	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22533	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22534	HAST	120°C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
P22535	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2401 DEC '98 TO-92 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9815	DM803085AAA	TO-92	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22922	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	93	DEVICE HRS: 9.89E+06		0
P22923	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22925	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2401 DEC '98 TO92 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9815	DM803085AAA	TO-92	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22908	INFANT LIFE	125°C, 6.0 VOLTS		234	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	635	DEVICE HRS:	1.44E+06	0
P22923	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22925	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2434 NOV '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2434	D1	9827	DM809170AAA	TO-226 (PR-35)	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22801	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	231	DEVICE HRS:	3.97E+06	0
P22858	TEMP CYCLE	-55 TO 125°C		50	300	CYCL	0
				50	1000	CYCL	0
		TOTAL:					0
P22860	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2502 SEP '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B6	9827	DM811458AAB	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ EPROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22573	INFANT LIFE	125°C, 7.0 VOLTS		233	48	HOUR	0
P22633	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS:	3.08E+07	0
P22506	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST		237	0		0
				237	0		0
		TOTAL:					0
P22634	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22635	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22636	HIGH TEMP STORAGE	150°C		39	336	HOUR	0
				39	1000	HOUR	0

RELIABILITY MONITOR

DS2502 SEP '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B6	9827	DM811458AAB	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ EPROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0

RELIABILITY MONITOR

DS2502S DEC '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	C2	9842	DM821478AIB	8 PIN SOIC	CARSEM

PROCESS Double Poly, Single Metal 0.6 µ EPROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P23041	INFANT LIFE	125°C, 7.0 VOLTS		228	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	240	DEVICE HRS:	3.82E+06	0
P22910	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST		232	0		0
				232	0		0
		TOTAL:					0

RELIABILITY MONITOR

DS2502 OCT '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B6	9822	DM810309ACB	6 PIN TSOC	CARSEM

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22683	HIGH TEMP STORAGE	125°C	151	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	151	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	151	3	PASS	0
		TOTAL:				0
P22741	TEMP CYCLE	-55 TO 125°C	77	300	CYCL	0
		-55 TO 125°C	77	1000	CYCL	0
		TOTAL:				0
P22742	AUTOCLAVE	121°C STEAM, UNBIASED	70	96	HOUR	0
		TOTAL:				0

RELIABILITY MONITOR

DS5002 APR 98 'MONITOR,DP.- CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9806	DM743264AAC	80 PIN PQFP	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Buried contacts w/silicided poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22249	INFANT LIFE	125°C, 7.0 VOLTS		199	48	HOUR	0
P22319	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.02E+07		0
P21907	HIGH TEMP STORAGE	125°C		203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		203	3	PASS	0
		TOTAL:					0
P22320	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22321	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				42	959	HOUR	0
		TOTAL:					0
P22322	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS5002 JUL '98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9822	DM808095AAE	80 PIN PQFP	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Buried contacts w/silicided poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22441	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	34	DEVICE HRS: 2.69E+07		0
P22247	HIGH TEMP STORAGE	125°C		203	25	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		203	3	PASS	0
		TOTAL:					0
P22442	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22443	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				42	959	HOUR	0
		TOTAL:					0
P22444	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS5002 JUL '98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9822	DM808095AAE	80 PIN PQFP	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Buried contacts w/silicided poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22364	INFANT LIFE	125°C, 7.0 VOLTS		199	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	276	DEVICE HRS:	3.32E+06	0
P22247	HIGH TEMP STORAGE	125°C		203	25	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		203	3	PASS	0
		TOTAL:					0
P22442	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22443	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				42	959	HOUR	0
		TOTAL:					0
P22444	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS5002 OCT '98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9831	DM817638AAF	80 PIN PQFP	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Buried contacts w/silicided poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22751	INFANT LIFE	125°C, 7.0 VOLTS		198	48	HOUR	0
P22769	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.02E+07		0
P22689	HIGH TEMP STORAGE	125°C		203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		203	3	PASS	0
		TOTAL:					0
P22770	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22771	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				42	959	HOUR	0
		TOTAL:					0
P22772	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS5002F JAN.'98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002F	A3	9738	DM720028AAC	80 PIN PQFP	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Buried contacts w/silicided poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21352	INFANT LIFE	125°C, 7.0 VOLTS		199	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	275	DEVICE HRS:	3.34E+06	0
P21282	HIGH TEMP STORAGE	125°C		203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		203	3	PASS	0
		TOTAL:					0
P21472	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21473	BIASED MOISTURE	85/85, 5.5 VOLTS		42	274	HOUR	0
				41	959	HOUR	0
		TOTAL:					0
P21474	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS80320 JUL '98 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9815	DK804253AAA	40 PIN PDIP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Single Metal 0.8 µ Poly silicide

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22230	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22309	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22310	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22311	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22312	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS80320 OCT '98 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9823	DK810423AAB	40 PIN PDIP	ANAM-PI (ATP/AAPI)

PROCESS Single Poly, Single Metal 0.8 µ Poly silicide

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22690	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22728	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22729	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22730	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22731	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0